Modeling and Design of Integrated CMOS Circuit

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Message from the Guest Editors

One of the main challenges for the electronic research field is to cope with the rapidly progressing technology which, today, reaches the nanometer scale and ultra-low voltages. The areas of interest of this Special Issue include the modeling and design of innovative chips and embedded systems. Emerging technologies have raised relevant topics related to performances, power, and reliability that to need to be investigated.

The topics of this Special Issue are dedicated but not limited to the following:

System-on-a-chip;

multiprocessor systems;

network-on-a-chip;

low-voltage and low-power systems;

Internet of Things sensor;

analog–digital convertor/digital–analog converter;

clock network;

emerging type of memories;

CMOS image sensors

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Message from the Editor-in-Chief

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